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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application

Inventors: H. SADAKATA, et al.

Art Unit: 2818

Application No.: 10/624,890

Filed: July 23, 2003

For: SEMICONDUCTOR MEMORY DEVICE AND TEST METHOD  
THEREOF

REQUEST FOR CORRECTED FILING RECEIPT

Assistant Commissioner of Patents  
Washington, D.C. 20231

Sir:

Please issue a Corrected Filing Receipt reflecting the title of the invention as set forth in the Declaration for Patent Application filed December 18, 2003, to read as follows: --SEMICONDUCTOR MEMORY DEVICE AND TEST METHOD THEREOF--.

A copy of the Filing Receipt with changes marked in red ink is attached.

Respectfully submitted,

James E. Ledbetter  
Registration No. 28,732

Date: June 9, 2004

JEL/mat

ATTORNEY DOCKET NO. L8462.03107

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APPL NO.	FILING OR 371 (c) DATE	ART UNIT	FIL FEE REC'D	ATTY. DOCKET NO	DRAWINGS	TOT CLMS	IND CLMS
10/624,890	07/23/2003	2818	1492	L8462.03107	9	13	5

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CONFIRMATION NO. 6756  
 UPDATED FILING RECEIPT



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Date Mailed: 03/25/2004

Receipt is acknowledged of this regular Patent Application. It will be considered in its order and you will be notified as to the results of the examination. Be sure to provide the U.S. APPLICATION NUMBER, FILING DATE, NAME OF APPLICANT, and TITLE OF INVENTION when inquiring about this application. Fees transmitted by check or draft are subject to collection. Please verify the accuracy of the data presented on this receipt. If an error is noted on this Filing Receipt, please write to the Office of Initial Patent Examination's Filing Receipt Corrections, facsimile number 703-746-9195. Please provide a copy of this Filing Receipt with the changes noted thereon. If you received a "Notice to File Missing Parts" for this application, please submit any corrections to this Filing Receipt with your reply to the Notice. When the USPTO processes the reply to the Notice, the USPTO will generate another Filing Receipt incorporating the requested corrections (if appropriate).

## Applicant(s)

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## Domestic Priority data as claimed by applicant

## Foreign Applications

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Projected Publication Date: 07/01/2004

Non-Publication Request: No

Early Publication Request: No

## Title

*test method thereof*  
 Semiconductor memory device and ~~method for testing the same~~

## Preliminary Class